CLAIMS

What is claimed is:

- 1 1. A photolithographic apparatus for use in a
- 2 photolithographic system for projecting light onto a
- workpiece, said photolithographic apparatus comprising a
- 4 container containing a transparent fluid, said container
- 5 having a bottom membrane contacting an upper surface of the
- 6 workpiece and overlapping at least one side edge of the
- 7 workpiece such that a fluid filled skirt is formed
- 8 extending beyond the at least one edge of the workpiece.
- 1 2. The photolithographic apparatus of claim 1, wherein the
- fluid filled skirt is formed at the side edge of the
- workpiece such that the bottom membrane substantially
- 4 contacts and conforms to the surface contour of the upper
- surface and the at least one side edge of the workpiece.
- 1 3. The photolithographic apparatus of claim 1, wherein the
- 2 bottom membrane comprises a flexible, liquid impermeable
- 3 membrane.
- 1 4. The photolithographic apparatus of claim 1, wherein the
- bottom membrane comprises a transparent material.
- 1 5. The photolithographic apparatus of claim 1, wherein the
- workpiece is a semiconductor wafer.
- 1 6. The photolithographic apparatus of claim 5, wherein the
- 2 upper surface of the semiconductor wafer is coated with a
- 3 photoresist material.

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- 1 7. The photolithographic apparatus of claim 1, wherein the
- 2 bottom membrane provides vertical containment of the
- optical transmission fluid, said container further
- 4 including a side wall member coupled to said bottom
- 5 membrane, said side wall providing horizontal fluid
- 6 containment.
- 1 8. The photolithographic apparatus of claim 7, said side
- wall member coupling the bottom membrane to a top membrane
- 3 to form a substantially liquid impermeable container
- 4 enclosure.
- 9. The photolithographic apparatus of claim 8, further
- comprising a final lens element disposed over and in
- 3 substantial abutment with the top membrane.
- 1 10. The photolithographic apparatus of claim 9, wherein
- 2 said final lens element is a photolithographic lens cover.
- 1 11. The photolithographic apparatus of claim 7, wherein
- said side wall member and bottom membrane form an open
- 3 fluid container externally accessible from above.
- 1 12. The photolithographic apparatus of claim 11, further
- 2 comprising a lens apparatus disposed over the open fluid
- 3 container.
- 1 13. The photolithographic apparatus of claim 12, wherein
- 2 said lens apparatus includes a final lens element
- 3 contacting the fluid within the container.

- 1 14. A projection exposure apparatus providing
- photolithographic processing of a semiconductor workpiece,
- 3 said projection exposure apparatus comprising a fluid
- 4 container having a bottom membrane and a side wall member
- 5 defining an open reservoir containing a transparent fluid,
- 6 wherein said container is disposed over the semiconductor
- 7 workpiece such that the bottom membrane lays in contact
- 8 with at least a portion of the upper surface of the
- 9 semiconductor workpiece.
- 1 15. The projection apparatus of claim 14, wherein the
- bottom membrane of said container is transparent.
- 1 16. The projection apparatus of claim 14, wherein the
- 2 bottom membrane comprises a flexible material such that the
- 3 lower outer surface of the open fluid reservoir
- 4 substantially conforms to the surface contour of the upper
- surface of the semiconductor workpiece.
- 1 17. The projection apparatus of claim 14, wherein the
- 2 bottom member overlaps at least one side edge of the
- 3 semiconductor workpiece such that a fluid filled skirt is
- 4 formed extending beyond the at least one edge of the
- semiconductor workpiece.
- 1 18. The projection apparatus of claim 14, wherein the
- 2 semiconductor workpiece comprises a semiconductor wafer.

- 1 19. A photolithographic system for projecting light onto a
- workpiece, said photolithographic system comprising:
- a fluid container having a transparent bottom membrane
- and a side wall member defining an open reservoir
- 5 containing a liquid, wherein said container is disposed
- over the semiconductor workpiece such that the bottom
- membrane contacts at least a portion of the upper surface
- of the semiconductor workpiece; and
- a lens assembly disposed over the open reservoir such
- that a final lens element is at least partially immersed
- 11 within the liquid.
- 1 20. The photolithographic system of claim 19, further
- 2 comprising liquid circulation means for establishing liquid
- 3 flow on the bottom surface of the final lens element.